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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Sheet 1 of 1

	Complete if Known
Application Number	10/666,765
Filing Date	Sep. 17, 2003
First Named Inventor	Mahesh A. Iyer
Art Unit	~~2184~~ 2129
Examiner Name	Joseph P. Hirl
Attorney Docket Number	06816.0506CON1

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.[1]	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T[2]
/JH/	1	A. Aharon, A. Bar-David, B. Dorfman, E. Gofman, M. Leibowitz, and V. Schwartzburd, "Verification of the IBM RISC System/6000 by a Dynamic Biased Pseudo-Random Test Program Generator", IBM Systems Journal, Vol. 30, No. 4, 1991, pp. 527-538.	
/JH/	2	E. Bin, R. Emek, G. Shurek, and A. Ziv, "Using a Constraint Satisfaction Formulation and Solution Techniques for Random Test Program Generation", IBM Systems Journal, Vol. 41, No. 3, 2002, pp. 386-400.	
/JH/	3	A. K. Chandra and V. S. Iyengar, "Constraint Solving for Test Case Generation", Proceedings of International Conference on Computer Design, 1992, pp. 245-248.	
/JH/	4	A. K. Chandra, V. S. Iyengar, D. Jameson, R. Jawalekar, I. Nair, B. Rosen, M. Mullen, J. Yoon, R. Armoni, D. Geist, and Y. Wolfsthal, "AVPGEN – A Test Case Generator for Architecture Verification", IEEE Transactions on VLSI Systems, Vol. 3, No. 2, June 1995, pp. 188-200.	
/JH/	5	C.-Y. Huang and K.-T. Cheng, "Assertion Checking by Combined Word-level ATPG and Modular Arithmetic Constraint-Solving Techniques", Proceedings of the Design Automation Conference, June 2000.	
/JH/	6	M. A. Iyer, "High Time for High-Level ATPG", Panel position statement, Proceedings of the International Test Conference, 1999, pp. 1112.	
/JH/	7	W. Kunz, and D. Pradhan, "Recursive Learning: A New Implication Technique for Efficient Solutions to CAD-problems - Test, Verification and Optimization", IEEE Transactions on Computer-Aided Design, Vol. 13, No. 9, September 1994, pp. 1143-1158.	
/JH/	8	I. Yuan, K. Shultz, C. Pixley, H. Miller, and A. Aziz, "Modeling Design Constraints and Biasing in Simulation Using BDDs", Proceedings of the International Conference on Computer-Aided Design, November 1999, pp. 584-589.	

Examiner Signature	/JH/	Date Considered	12/7/5

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